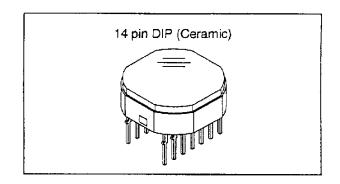
ICX058AKB

Diagonal 6mm (Type 1/3) CCD Image Sensor for NTSC Color Camera

Description

The ICX058AKB is an interline transfer CCD solidstate image sensor suitable for NTSC color video cameras. High sensitiveness and low dark current are achieved through the adoption of Ye, Cy, Mg and G complementary color mosaic filters and HAD (Hole-Accumulation Diode) sensors.

This chip features a field integration read out system and an electronic shutter with variable charge-storage time. Also, this outline is miniaturized by using original package.



Features

- · High image, high sensitivity and low dark current
- Consecutive various speed shutter 1/60s (Typ.), 1/100s to 1/10000s
- Low smear
- High antiblooming
- Ye, Cy, Mg, G on chip type complementary color mosaic filter.
- Horizontal register 5V drive
- Reset gate 5V drive

Device Structure

Image size

Diagonal 6mm (Type 1/3)

Number of effective pixels

768 (H) ×494 (V) Approx. 380k pixels

Number of total pixels

811 (H) ×508 (V) Approx. 410k pixels

Interline transfer CCD image sensor

Chip size

6.00mm (H) ×4.96mm (V)

Unit cell size

6.35 μm (H) ×7.4 μm (V)

Optical black

Horizontal (H) direction Front 3 pixels Rear 40 pixels

Vertical (V) direction

Front 12 pixels Rear 2 pixels

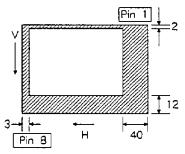
Number of dummy bits Horizontal

Vertical

1 (even field only)

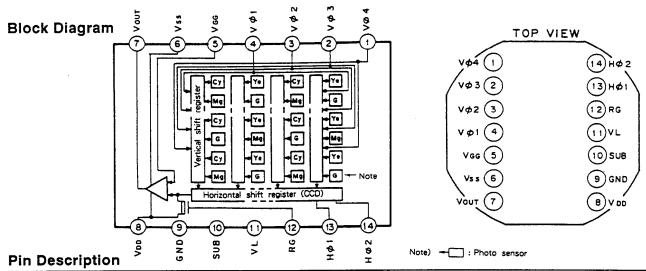
Board material

N-type silicon



Optical black position (Top View)

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No.	Symbol	Description	No.	Symbol	Description
1	Vφ4	Vertical register transfer clock	8	VDD	Output amplifier drain supply
2	Vфз	Vertical register transfer clock	9	GND	GND
3	V ф 2	Vertical register transfer clock	10	SUB	Substrate (Overflow drain)
4	Vф1	Vertical register transfer clock	11	VL	Protective transistor bias
5	Vgg	Output amplifier gate bias	12	RG	Reset gate clock
6	Vss	Output amplifier source	13	Нф1	Horizontal register transfer clock
7	Vout	Signal output	14	Нф2	Horizontal register transfer clock

Absolute Maximum Ratings

	Item	Ratings	Unit	Remarks
Substrate voltage S	UB-GND	-0.3 to +55	V	
0	VDD, VOUT, VSS — GND	-0.3 to +18	V	
Supply voltage	VDD, VOUT, VSS — SUB	-55 to +10	V	
Vertical clock	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
input voltage	Vφ1, Vφ2, Vφ3, Vφ4 — SUB	to +10	V	
Voltage difference b	petween vertical clock input pins	to +15	V	*
Voltage difference b	petween horizontal clock input pins	to +17	V	
Hф1, Hф2-Vф4		-17 to +17	٧	
Ηφ1, Ηφ2, RG, Vga	- GND	-10 to +15	٧	
Ηφ1, Ηφ2, RG, Vgc	- SUB	-55 to +10	V	
VL - SUB		-65 to +0.3	V	
Vφ1, Vφ2, Vφ3, V¢	4, VDD, VOUT-VL	-0.3 to +30	V	
RG-VL		-0.3 to +24	V	
Vgg, Vss, Hφ1, Hφ	2–VL	-0.3 to +20	٧	
Storage temperatur	е	-30 to +80	ొ	
Operating temperat	ure	-10 to +60	℃	

^{* +27}V (Max.) when clock width < 10 μ s, duty factor < 0.1%.

Bias Conditions

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain voltage	VDD	14.55	15.0	15.45	٧	
Output amplifier gate voltage	Vgg	3.8	4.2	4.65	V	
Output amplifier source	Vss		ound throus 0 Ω resis			±5%
Substrate voltage adjustment range	VsuB	9.0		18.5	V	*2
Fluctuation range after substrate voltage adjustment	ΔVsuB	-3		+3	%	
Reset gate clock voltage adjustment range	VRGL	1.0		4.0	V	*2 *6
Fluctuation range after reset gate clock voltage adjustment	∆VRGL	-3		+3	%	
Protective transistor bias	VL		*3	1.,		

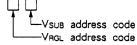
DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain current	aal		5		mA	
Input current	lin1			1	μΑ	*4
Input current	liN2			10	μА	*5

*2 Substrate voltage (Vsub) • reset gate clock voltage (Vrgl.) setting value display.

Setting values of substrate voltage and reset gate clock voltage are displayed at the back of the device through a code address. Adjust substrate voltage (Vsub) and reset gate clock voltage (Vrgl.) to the displayed voltage. Fluctuation range after adjustment is ±3%.

Vsus code address–1 digit display VRGL code address–1 digit display



Code addresses and actual numerical values correspond to each other as follows.

VRGL addre	ss c	ode		1	2	3 4	5	6	7											
Numerical	value	•		1.0	1.5 2	.0 2.	5 3.0	3.5	4.0											•
Vsus address code	E	f	G	h	J	к	L	m	N	Р	Q	R	S	Т	U	٧	w	x	Y	z
Numerical value	9.0	9.5	10.0	10.5	5 11.0	11.5	12.0	12.5	13.0	13.5	14.0	14.5	15.0	15.5	16.0	16.5	17.0	17.5	18.0	18.5

*3 VL setting is the VvL voltage of the vertical transfer clock waveform.

- *4 1. Current to each pin when 18V is applied to Vpp, Vouт, Vss and SUB pins, while pins that are not tested are grounded.
 - 2. Current to each pins when 20V is applied sequentially to Vφ1, Vφ2, Vφ3 and Vφ4, while pins that are not tested are grounded. However, 20V is applied to SUB.
 - 3. Current to each pins when 15V is applied sequentially to pins RG, H \phi 1, H \phi 2 and Vgg, while pins that are not tested are grounded. However, 15V is applied to SUB.
 - 4. Apply 30V to Pins V φ 1, V φ 2, V φ 3, V φ 4, V DD, V OUT; 24V to Pin RG; and 20V to Pins V GG, Vss, H φ 1, H φ 2. The above is the current that flows to Pin V L when it is grounded. Please note that Pins GND and SUB are to be disconnected.
- *5 Current to SUB pin when 55V is applied to SUB pin, while pins that are not tested are grounded.

Clock Voltage Conditions

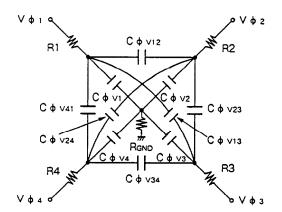
ltem	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Read out clock voltage	Vvт	14.55	15.0	15.45	٧	1	
	VvH1, VvH2	-0.05	0	0.05	٧	2	VvH=(VvH1+VvH2)/2
	VvH3, VvH4	-0.2	0	0.05	٧	2	
	VVL1, VVL2, VVL3, VVL4	-9.0	-8.5	-8.0	٧	2	VvL=(VvL3+VvL4)/2
	Vφv	7.8	8.5	9.05	٧	2	V ф v=Vvнn-VvLn (n=1 to 4)
Vertical transfer clock	VvH1-VvH2			0.1	٧	2	
voltage	Vvнз–Vvн	-0.25		0.1	V	2	
	VvH4–VvH	-0.25		0.1	٧	2	
	Vvнн			0.5	٧	2	High level coupling
	VVHL			0.5	٧	2	High level coupling
	VVLH			0.5	٧	2	Low level coupling
	VVLL			0.5	٧	2	Low level coupling
Horizontal transfer	Vфн	4.75	5.0	5.25	٧	3	
clock voltage	VHL	-0.05	0	0.05	٧	3	
Reset gate clock	V ф RG	4.5	5.0	5.5	٧	4	*6
voltage	VRGLH-VRGLL			0.8	٧	4	Low level coupling
Substrate clock voltage	Vфsuв	22.5	23.5	24.5	٧	5	

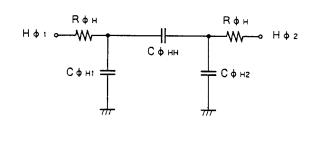
^{*6} No adjustment of reset gate clock voltage is necessary when reset gate clock is driven as indicated below. In this case, reset gate clock voltage set point displayed on back of image sensor has no meaning.

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	VRGL	-0.2	0	0.2	٧	4	
voltage	VφRG	8.5	9.0	9.5	٧	4	

Clock Equivalent Circuit Constant

ltem	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer	Сфу1, Сфуз		1000		pF	
clock and GND	Сф ∨2, Сф ∨4		560		pF	
	Сф V12, Сф V34		470		pF	
Capacitance between vertical transfer	Сф V23, Сф V41		330		pF	
clocks	Сфу13		220		pF	
	Сф ∨24		100		рF	
Capacitance between horizontal transfer clock and GND	Сфн1, Сфн2		47		pF	
Capacitance between horizontal transfer clocks	Сфин		43		рF	
Capacitance between reset gate clock and GND	Сфяс		8		рF	
Capacitance between substrate clock and GND	Сфѕив		270		pF	
Vertical transfer clock serial resistor	R1, R2, R3, R4		80		Ω	
Vertical transfer clock ground resistor	RGND		15		Ω	
Horizontal transfer clock serial resistor	Rфн		15		Ω	



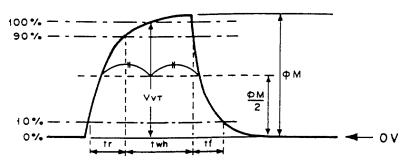


Vertical transfer clock equivalent circuit

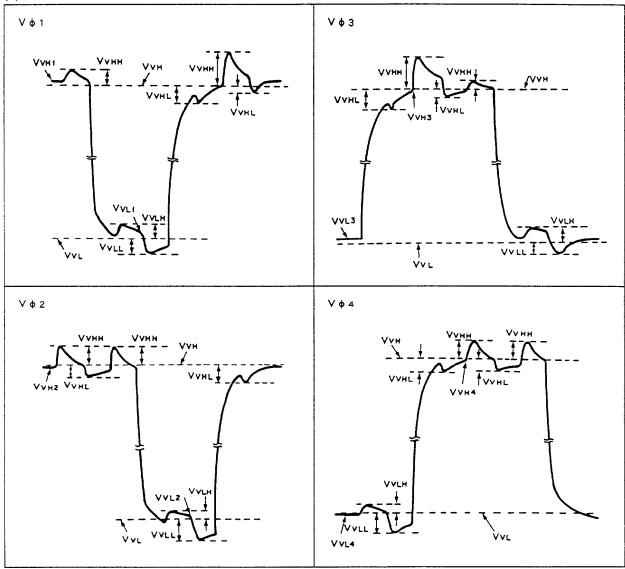
Horizontal transfer clock equivalent circuit

Drive Clock Waveform Conditions

(1) Read out clock waveform



(2) Vertical transfer clock waveform

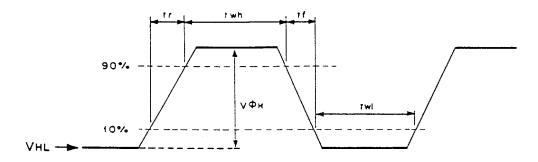


VvH=(VvH1+VvH2)/2

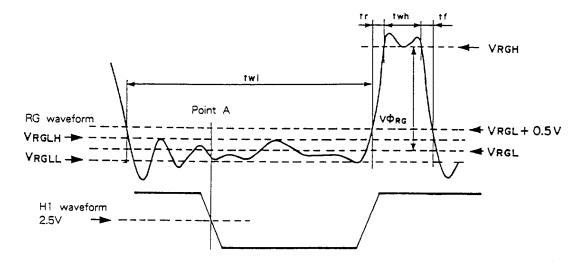
VvL=(VvL3+VvL4)/2

 $V\phi v=VvHn-VvLn$ (n=1 to 4)

(3) Horizontal transfer clock waveform diagram



(4) Reset gate clock waveform diagram



VRGLH is the maximum value and VRGLL the minimum value of the coupling waveform in the period from Point A in the diagram above to RG rise.

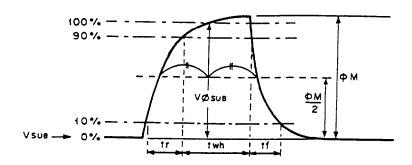
VRGL is the mean value for VRGLH and VRGLL.

VRGL=(VRGLH+VRGLL)/2

VAGH is the minimum value for twh period.

 $V \phi RG = VRGH - VRGL$

(5) Substrate clock waveform



Clock Switching Characteristics

	Item	Symbol		twh			twl			tr			tf			
		Symbol	Min.	Тур.	Max.	Unit	Remarks									
Read	l out clock	Vī	2.3	2.5						0.5			0.5		μs	During read out
Vertic clock	cal transfer	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*7
sfer	During	Нф1	18	24		19.5	26			10	17.5		10	17.5	ns	
trans	imaging	Нф2	21	26		19	24			10	15		10	15	ns	*8
Horizontal transfer clock	During parallel	Нф1		5.38						0.01			0.01		μs	***
Horiz	serial conversion	Нф2					5.38			0.01			0.01		μs	
Rese	t gate clock	ф RG	11	13			51			3		*	3		ns	
Subs	trate clock	фѕив	1.5	1.8							0.5			0.5	μs	During charge drain.

^{*7} When vertical transfer clock driver CXD1250 is in use.

^{*8} If \geq tr-2 ns, and the crosspoint voltage (VcR) of the H ϕ 1 rise side of waveforms H ϕ 1 and H ϕ 2 must be at least 2.5V.

Item	Symbol		two		Linit	Domarka
item	Symbol	Min.	Тур.	Max.	Offic	Remarks
Horizontal transfer clock	Нф1, Нф2	16	20		ns	*9

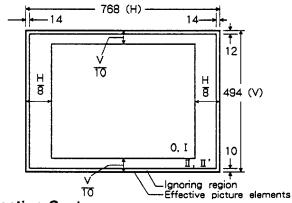
^{*9 &}quot;two" is the overlap period of horizontal transfer clocks $H\phi_1$ and $H\phi_2$'s twh and twl.

Operating Characteristics

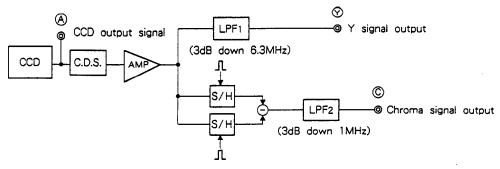
(Ta=25 °C)

item	Symbol	Min.	Тур.	Max.	Unit	Test method	Remarks
Sensitivity	S	270	340		mV	1	
Saturation signal	Ysat	600			mV	2	Ta=60 °C
Smear	Sm		0.009	0.015	%	3	
Video sissed shedise	CU			20	%	4	Zone 0, I
Video signal shading	SHy			25	%	4	Zone 0 to II'
Uniformity between signal	∆ Sr			10	%	5	
channels	ΔSb			10	%	5	
Dark signal	Ydt			2	mV	6	Ta=60 °C
Dark signal shading	∆ Ydt			1	mV	7	Ta=60 °C
Flicker Y	Fy			2	%	8	
Flicker R-Y	Fcr			5	%	8	
Flicker B-Y	Fcb			5	%	8	
Horizontal stripes R	Lcr			3	%	9	
Horizontal stripes G	Lcg			3	%	9	
Horizontal stripes B	Lcb			3	%	9	
Horizontal stripes W	Lcw			3	%	9	
Lag	Lag			0.5	%	10	

Zone chart of Video signal shading



Testing System

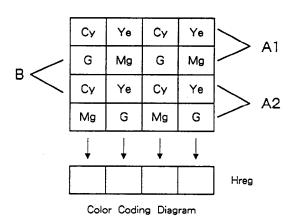


Note) Adjust AMP amplifier so that total gains between (△) and (○) and between (△) and (○) equal 1.

Image Sensor Characteristics Test Method

Test conditions

- 1 Through the following tests the substrate voltage and reset gate clock voltage are set to the value displayed on the device, while the device drive conditions are at the typical value of the bias and clock voltage conditions.
- 2 Through the following tests defects are excluded and, unless otherwise specified, the optical black level (Hence forth referred to as OB) is set as the reference for the signal output which is taken as the Y signal output or the chroma signal output of the testing system.
- © Color coding of CFA (Color Filter Array) & Composition of luminance (Y) and chrominance (C) signals



CFA of this image sensor is shown in the Figure. This complementary CFA is used with a "field integration mode", where all of the photosites are read out during each video field. Signals from two vertically adjacent photosites, such as line A1 or A2 for field A, are summed when the image charge is transferred into the vertical storage columns.

The read out line pairing is shifted down one line for field B. The sensor output signals through the horizontal register (H reg.) at line A1 are [G+Cy], [Mg+Ye], [G+Cy], [Mg+Ye].

These signals are processed in order to compose Y and C signals. By adding the two adjacent signals at line A1, Y signal is formed as follows:

$$Y = \{(G+Cy)+(Mg+Ye)\} \times 1/2$$

=1/2 {2B+3G+2R}

C signal is composed by subtracting the two adjacent signals at line A1.

$$R - Y = \{(Mg+Ye)-(G+Cy)\}$$
$$= \{2R-G\}$$

Next, the signals through H reg. at line A2 are

[Mg+Cy], [G+Ye], [Mg+Cy], [G+Ye]

Similarly, Y and C signals are composed at line A2.

$$Y = \{(G+Ye)+(Mg+Cy)\} \times 1/2$$

$$=1/2{2B+3G+2R}$$

$$-(B-Y) = \{(G+Ye)-(Mg+Cy)\}$$

=-{2B-G}

Accordingly, Y signal is balanced in relation to the scanning lines, and C signal takes the form of R-Y and -(B-Y) on alternate lines.

It is the same for B field.

Definition of standard imaging conditions

- ① Standard imaging condition I: (As imaging device) Use a pattern box (luminance 706 cd/ m², color temperature 3200K Halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t=1.0mm) as IR cut filter and image at F5.6. At this time, light intensity to sensor receiving surface is defined as standard sensitivity testing light intensity.
- ② Standard imaging condition II: Image a light source (color temperature of 3200K) which uniformity of brightness is within 2% at all angles. Use a testing standard lens with CM500S (t=1.0mm) as IR cut filter. The light intensity is adjusted to the value indicated in each testing item by lens diaphragm.

1. Sensitivity

Set to standard image condition I. After selecting the electronic shutter mode at a 1/250s. shutter speed, measure the Y signal (Ys) at the center of the screen and substitute in the following formula.

$$S = Ys \times \frac{250}{60}$$
 [mV]

2. Saturation signal

Set to standard imaging condition II. Adjust light intensity to 10 times that of Y signal output average value (Ya=200mV), then test Y signal minimum value.

3. Smear

Set to standard imaging condition II. Adjust light intensity to 500 times that of Y signal output average value (Ya=200mV) with lens diaphragm at F5.6 to F8. Stop read out clock. When the charge drain executed by the electronic shutter at the respective H blankings takes place, test the maximum value YSm [mV] of Y signal output.

$$Sm = \frac{YSm}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 (\%) (1/10V)$$

4. Video signal shading

Set to standard imaging condition π . Adjust light intensity to Y signal output average value (Y_A=200mV) with lens diaphragm at F5.6 to F8. Then test maximum (Ymax [mV]) and minimum (Ymin [mV]) values of Y signal.

5. Video signal between channels uniformity

Set to standard imaging condition II. Adjust light intensity to Y signal output average value (YA=200mV). Then test maximum (Crmax, Cbmax [mV]) and minimum (Crmin, Cbmin [mV]) values of chroma signals from R-Y and B-Y channels.

$$\Delta$$
 Sr = |(Crmax-Crmin) /200| × 100 (%)
 Δ Sb= |(Cbmax-Cbmin) /200| × 100 (%)

6. Dark signal

Test Y signal output average value Ydt [mV] when the device ambient temperature is at 60 °C and light is obstructed with horizontal idle transfer level as reference.

7. Dark signal shading

Following 6, test maximum (Ydmax [mV]) and minimum (Ydmin [mV]) values of dark signal output.

8. Flicker

① Fy

Set to standard imaging condition II. Adjust light intensity to Y signal output average value (YA=200mV). Then test the Y signal difference (Δ Yf [mV]) between even field and odd field.

Fy= (
$$\triangle$$
 Yf/200) ×100 (%)

2 Fcr, Fcb

Set to standard imaging condition II. Adjust light intensity to Y signal output average value (YA=200mV). Then insert R or B filter, and test the C signal difference (Δ Cr, Δ Cb) between even field and odd field and the C signal output average value (CAr, CAb).

Fci= (
$$\triangle$$
 Ci/CAi) × 100 (%) (i=r, b)

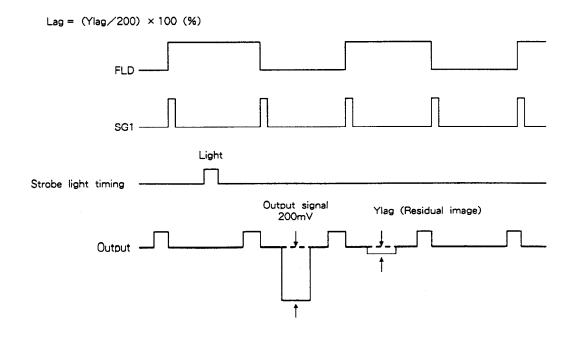
9. Lateral stripe

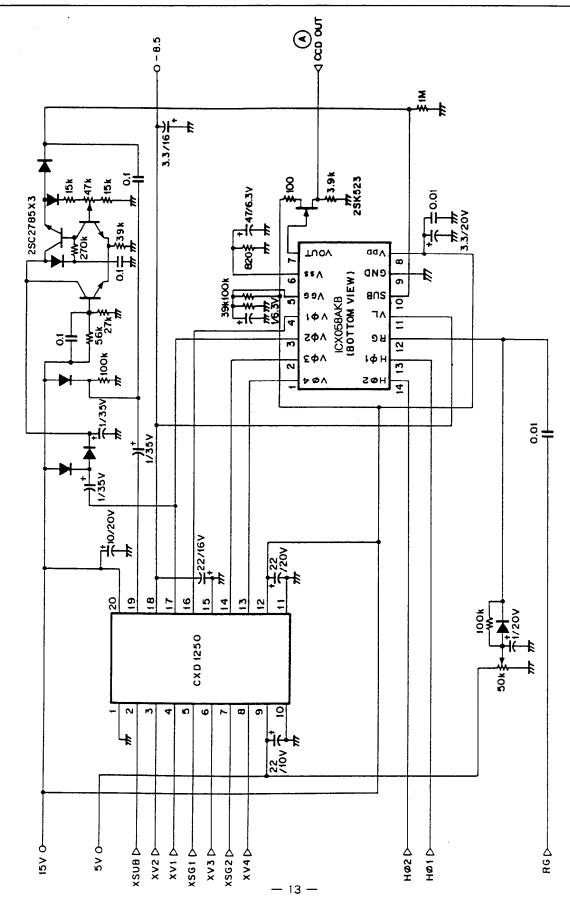
Set to standard imaging condition II. Adjust light intensity to Y signal output average value (YA=200mV). Then insert R, G and B filters respectively, and test the signal difference (Δ Ylw, Δ Ylr, Δ Ylg, Δ Ylb [mV]) between Y signal lines of the same field.

Lci= (
$$\triangle$$
 Yli/200) × 100 (%) (i=w, r, g, b)

10. Residual image

Adjust Y signal output value by strobe light to 200mV. Then light a stroboscopic tube with the following timing and test the residual image (Ylag).

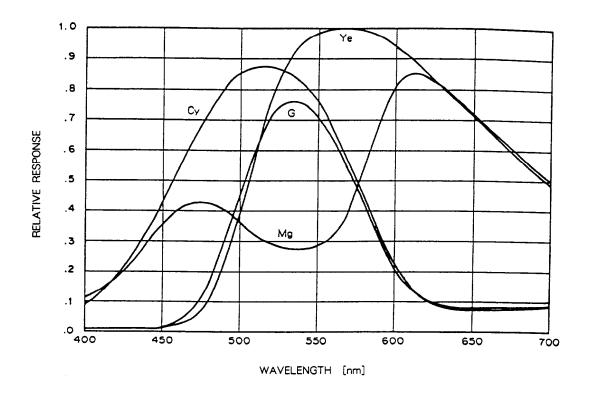




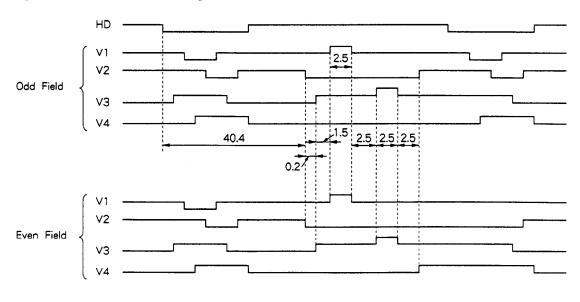
Drive Circuit

Spectral Sensitivity Characteristics

(Excluding light source characteristics, including lens characteristics)



Using Read Out Clock Timing Chart

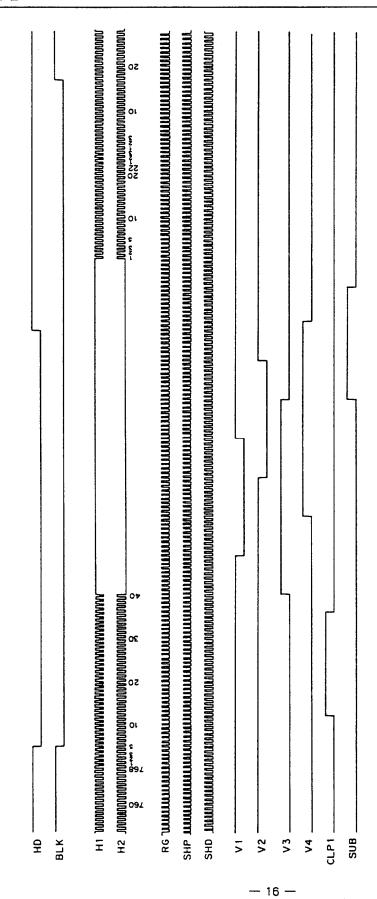


Unit: µs

oez 27S 07S S9Z 560 οz Drive Timing Chart (Vertical sync) v3 ozs 2 861 **S**62

— 15 —

Drive Timing Chart (Horizontal sync)



Notes on Handling

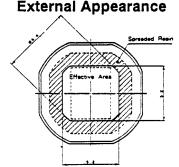
- 1) Static charge prevention
 - CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.
- a) Either handle bare handed or use non-chargeable gloves, clothes or material.
 Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) lonized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.
- 3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

- a) Operate in clean environments (around class 1000 is appropriate).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.
- 4) Do not expose to strong light (sun rays) for long periods, color filters will be discolored. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- 5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to too much mechanical shocks.
- 7) Eclipse (to get dark around the four corners of the picture) may occur when some object lenses are in the open iris state.



17



